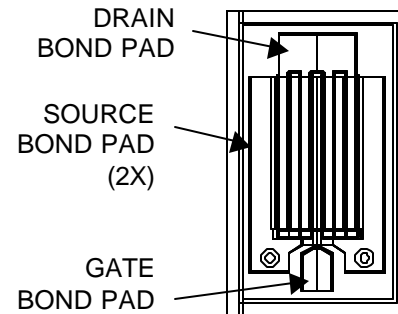


**FEATURES**

- ◆ 48 dBm IP3 at 2 GHz
- ◆ 34 dBm P-1dB at 2 GHz
- ◆ 14 dB Power Gain at 2 GHz


**DESCRIPTION AND APPLICATIONS**

The FP4050 is an Aluminum Gallium Arsenide / Indium Gallium Arsenide (AlGaAs/InGaAs) Pseudomorphic High Electron Mobility Transistor (PHEMT), utilizing an Electron-Beam direct-write 0.50  $\mu\text{m}$  by 400  $\mu\text{m}$  Schottky barrier gate. The recessed “mushroom” gate structure minimizes parasitic gate-source and gate resistances. The FP4050 features Si<sub>3</sub>N<sub>4</sub> passivation.

Typical applications include commercial and military high-performance power amplifiers, including SATCOM uplink transmitters, PCS/Cellular low-voltage high-efficiency output amplifiers, and medium-haul digital radio transmitters. This device is also suitable as a power stage for WLAN and ISM band spread spectrum applications.

**ELECTRICAL SPECIFICATIONS @  $T_{\text{Ambient}} = 22 \pm 3 \text{ }^\circ\text{C}$** 

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Output Power @ 1dB Compression	$P_{1dB}$	$f = 2 \text{ GHz}; V_{DS} = 8\text{V}; I_{DS} = 50\% I_{DSS}$		34		dBm
Power Gain @ 1dB Compression	$G_{1dB}$	$f = 2 \text{ GHz}; V_{DS} = 8\text{V}; I_{DS} = 50\% I_{DSS}$		14		dB
Saturated Drain-Source Current	$I_{DSS}$	$V_{DS} = 2\text{V}; V_{GS} = 0\text{V}$	950	1100	1300	mA
Maximum Drain-Source Current	$I_{MAX}$	$V_{DS} = 2\text{V}; V_{GS} = 1\text{V}$		2200		mA
Transconductance	$G_M$	$V_{DS} = 2 \text{ V}; V_{GS} = 0 \text{ V}$		880		mS
Pinch-Off Voltage	$V_P$	$V_{DS} = 2 \text{ V}; I_{DS} = 10 \text{ mA}$		-1.2		V
Gate-Drain Breakdown Voltage Magnitude	$ V_{BDGD} $	$I_{GS} = 20 \text{ mA}$	12	15		V
Gate-Source Breakdown Voltage Magnitude	$ V_{BDGS} $	$I_{GS} = 20 \text{ mA}$	12	15		V
Gate-Source Leakage Current Magnitude	$ I_{GSL} $	$V_{GS} = -5 \text{ V}$			0.2	mA
Thermal Resistivity	$\theta_{JC}$			15		$^\circ\text{C/W}$

- RECOMMENDED CONTINUOUS OPERATING LIMITS**

Parameter	Symbol	Nominal	Units
Drain-Source Voltage	$V_{DS}$	8	V
Gate-Source Voltage	$V_{GS}$	-1.0	V
Drain-Source Current	$I_{DS}$	500	mA
RF Input Power	$P_{IN}$	800	mW
Channel Operating Temperature	$T_{CH}$	150	°C
Ambient Temperature	$T_{STG}$	-20/50	°C

Note: Device should be operated at or below Recommended Continuous Operating Limits for reliable performance.

- ABSOLUTE RATINGS**

Parameter	Symbol	Test Conditions	Min	Max	Units
Drain-Source Voltage	$V_{DS}$	$T_{Ambient} = 22 \pm 3 \text{ }^{\circ}\text{C}$		10	V
Gate-Source Voltage	$V_{GS}$	$T_{Ambient} = 22 \pm 3 \text{ }^{\circ}\text{C}$		-5	V
Drain-Source Current	$I_{DS}$	$T_{Ambient} = 22 \pm 3 \text{ }^{\circ}\text{C}$		800	mA
Gate Current	$I_G$	$T_{Ambient} = 22 \pm 3 \text{ }^{\circ}\text{C}$		180	mA
RF Input Power	$P_{IN}$	$T_{Ambient} = 22 \pm 3 \text{ }^{\circ}\text{C}$		TBD	mW
Channel Operating Temperature	$T_{CH}$	$T_{Ambient} = 22 \pm 3 \text{ }^{\circ}\text{C}$		175	°C
Storage Temperature	$T_{STG}$	—	-65	175	°C

Note: Even temporary operating conditions that exceed the Absolute Maximum Ratings could result in permanent damage to the device.

- HANDLING PRECAUTIONS**

To avoid damage to the devices care should be exercised during handling. Proper Electrostatic Discharge (ESD) precautions should be observed at all stages of storage, handling, assembly, and testing. These devices should be treated as Class 1A (0-500 V). Further information on ESD control measures can be found in MIL-STD-1686 and MIL-HDBK-263.

All information and specifications are subject to change without notice.